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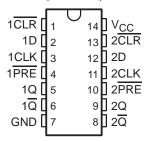
- EPIC[™] (Enhanced-Performance Implanted CMOS) Process
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC}, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 > 2 V at V_{CC}, T_A = 25°C
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Small-Outline (D, NS), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Packages, Chip Carriers (FK), and DIPs (J)

description

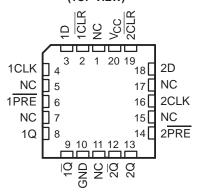
These dual positive-edge-triggered D-type flip-flops are designed for 2-V to 5.5-V $V_{\rm CC}$ operation.

A low level at the preset (PRE) or clear (CLR) inputs sets or resets the outputs, regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the data (D) inputs meeting the setup-time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

SN54LV74A . . . J OR W PACKAGE SN74LV74A . . . D, DB, DGV, NS, OR PW PACKAGE (TOP VIEW)



SN54LV74A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

The SN54LV74A is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74LV74A is characterized for operation from -40° C to 85° C.



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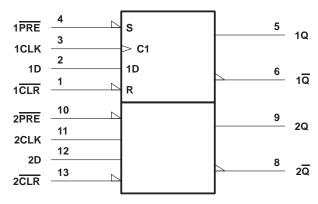
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FUNCTION TABLE

	INP	UTS		OUTI	PUTS
PRE	CLR	CLK	D	Q	Q
L	Н	Х	Χ	Н	L
Н	L	X	Χ	L	Н
L	L	X	Χ	H [†]	H [†]
Н	Н	\uparrow	Н	Н	L
Н	Н	\uparrow	L	L	Н
Н	Н	L	Χ	Q ₀	\overline{Q}_0

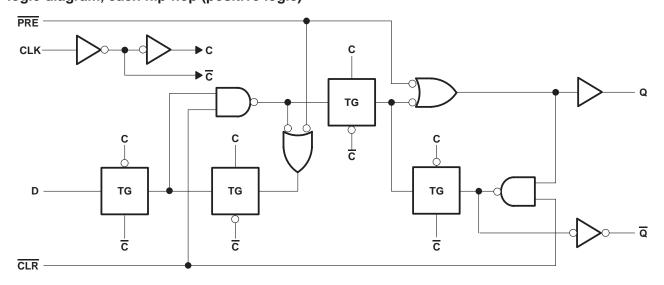
[†] This configuration is unstable; that is, it does not persist when PRE or CLR returns to its inactive (high) level.

logic symbol‡



 $[\]ddagger$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.

logic diagram, each flip-flop (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input voltage range, V _I (see Note 1)		0.5 V to 7 V
Output voltage range, V _O (see Notes 1 and 2)		$10.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$)		
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CO}$		
Continuous output current, I_O ($V_O = 0$ to V_{CC})		
Continuous current through V _{CC} or GND		
Package thermal impedance, θ _{JA} (see Note 3):		
,	DB package	
	DGV package	182°C/W
	NS package	127°C/W
	PW package	170°C/W
Storage temperature range, T _{sto}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. This value is limited to 7 V maximum.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			SN54L	.V74A	SN74	LV74A	UNIT
			MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage		2	5.5	2	5.5	V
		V _{CC} = 2 V	1.5		1.5		
\/	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V _{CC} ×0.7		V _{CC} × 0.7		V
VIH	nign-ievei input voitage	V _{CC} = 3 V to 3.6 V	V _{CC} ×0.7		$V_{CC} \times 0.7$]
		V _{CC} = 4.5 V to 5.5 V	V _{CC} ×0.7		$V_{CC} \times 0.7$		
		V _{CC} = 2 V		0.5		0.5	
\/	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	V
VIL	Low-level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	ľ
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	
VI	Input voltage		0	5.5	0	5.5	V
VO	Output voltage		0	Vcc	0	VCC	V
		V _{CC} = 2 V	3	- 50		-50	μΑ
la	High-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	90	-2		-2	
IOH	nign-ievei output current	V _{CC} = 3 V to 3.6 V	P	-6		-6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		-12		-12	
		V _{CC} = 2 V		50		50	μΑ
la.	Low-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2		2	
IOL	Low-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		6		6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		12		12	
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0	200	0	200	
$\Delta t/\Delta v$	Input transition rise or fall rate	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	0	100	0	100	ns/V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0	20	0	20	
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS	.,	SN54LV74A	SN74LV74A	UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN TYP MAX	MIN TYP MAX	UNII
	I _{OH} = -50 μA	2 V to 5.5 V	V _{CC} -0.1	V _{CC} -0.1	
\/a	I _{OH} = -2 mA	2.3 V	2	2	V
VOH	I _{OH} = -6 mA	3 V	2.48	2.48	V
	I _{OH} = -12 mA	4.5 V	3.8	3.8	
	I _{OL} = 50 μA	2 V to 5.5 V	0.1	0.1	
Voi	I _{OL} = 2 mA	2.3 V	0.4	0.4	V
VOL	I _{OL} = 6 mA	3 V	0.44	0.44	V
	I _{OL} = 12 mA	4.5 V	0.55	0.55	
lį	V _I = V _{CC} or GND	5.5 V	<u>±</u> 1	±1	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	20	20	μΑ
l _{off}	V_I or $V_O = 0$ to 5.5 V	0 V	5	5	μΑ
C.	V _I = V _{CC} or GND	3.3 V	2.1	2.1	pF
C _i	AL = ACC OL GIAD	5 V	2.1	2.1	pΓ

timing requirements over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

	PARAMETER		T _A = 2	25°C	SN54L	.V74A	SN74L	.V74A	UNIT
	PARAMETER		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
	Pulse duration	PRE or CLR low	8		9		9		ns
l _W	Fulse duration	CLK	8		9	N. W	9		115
	Cotion times before OLKA	Data	8		9	711	9		no
tsu	Setup time before CLK↑	PRE or CLR inactive	7		7		7		ns
t _h	Hold time, data after CLK↑		0.5		0.5		0.5		ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

	PARAMETER		$T_A = 2$	25°C	SN54L	.V74A	SN74L	V74A	UNIT
	FARAIVIETER		MIN	MAX	MIN	MAX	MIN	MAX	ONIT
	Pulse duration	PRE or CLR low	6		7	>	7		ns
t _W	ruise duration	CLK	6		7	10,71	7		115
	Saturations haters CLV	Data	6		7	M	7		ns
t _{su}	Setup time before CLK↑	PRE or CLR inactive	5		5		5		115
th	Hold time, data after CLK↑		0.5		0.5		0.5		ns

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timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

	PARAMETER		T _A = 2	25°C	SN54L	.V74A	SN74L	.V74A	UNIT
	PARAMETER		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
	Dulgo duration	PRE or CLR low	5		5	7	5		
t _W	Pulse duration	CLK	5		5	1001	5		ns
· ·	Satura time hafara CLIV [↑]	Data	5		5	ŽĮ,	5		no
t _{su}	Setup time before CLK↑	PRE or CLR inactive	3		3		3		ns
t _h	Hold time, data after CLK↑		0.5		0.5		0.5		ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	Վ = 25° C	;	SN54L	V74A	SN74L	.V74A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
,			C _L = 15 pF*	50	100		40	1/5	40		MHz
fmax			C _L = 50 pF	30	70		25	751	25		IVII IZ
4 .*	PRE or CLR	0 · · 0	C _I = 15 pF		9.8	14.8	1,4	17	1	17	no
^t pd*	CLK	Q or Q	CL = 15 pr		11.1	16.4	3	19	1	19	ns
4 .	PRE or CLR	Q or Q	C 50 pE		13	17.4	Q ₁	20	1	20	20
^t pd	CLK	QUIQ	C _L = 50 pF		14.2	20	2 1	23	1	23	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	ղ = 25°C	;	SN54L	V74A	SN74L	V74A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f f			C _L = 15 pF*	80	140		70	16	70		MHz
f _{max}			C _L = 50 pF	50	90		45	751	45		IVITZ
4 .*	PRE or CLR		C. 45 pF		6.9	12.3	1,	14.5	1	14.5	
t _{pd} *	CLK	Q or Q	C _L = 15 pF		7.9	11.9	3	14	1	14	ns
	PRE or CLR	Q or $\overline{\mathbb{Q}}$	C 50 pE		9.2	15.8	81	18	1	18	20
^t pd	CLK	QUIQ	$C_L = 50 pF$		10.2	15.4	Q 1	17.5	1	17.5	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

00	•		, ,	0	,						
PARAMETER	FROM	то	LOAD	T,	գ = 25°C	;	SN54L	V74A	SN74L	.V74A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f			C _L = 15 pF*	130	180		110	1/5/	110		MHz
fmax			C _L = 50 pF	90	140		75	?E1	75		IVII IZ
+ .*	PRE or CLR	0 0	C _I = 15 pF		5	7.7	1,	9	1	9	ns
^t pd*	CLK	Q or Q	CL = 15 pr		5.6	7.3	3	8.5	1	8.5	115
	PRE or CLR	Q or Q	C _I = 50 pF		6.6	9.7	Q ₁	11	1	11	ns
^t pd	CLK	QUQ	CL = 50 pr		7.2	9.3	2 1	10.5	1	10.5	115

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.



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noise characteristics, V_{CC} = 3.3 V, C_L = 50 pF, T_A = 25°C (see Note 5)

	PARAMETER	SN	174LV74	A	UNIT
	PARAMETER	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.1	0.8	V
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.04	-0.8	V
V _{OH(V)}	Quiet output, minimum dynamic VOH		3.2		V
VIH(D)	High-level dynamic input voltage	2.31			V
V _{IL(D)}	Low-level dynamic input voltage			0.99	V

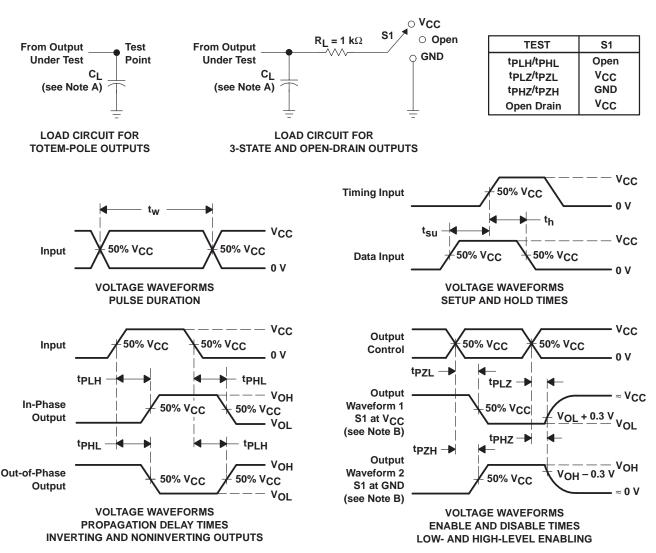
NOTE 5: Characteristics are for surface-mount packages only.

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	VCC	TYP	UNIT
C	Power dissipation capacitance	C ₁ = 50 pF, f = 10 MHz	3.3 V	21	pF
Cpd	i ower dissipation capacitance	$C_L = 50 \text{ pr}, f = 10 \text{ MHz}$	5 V	23	ρī

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 3 ns. $t_f \leq$ 3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLZ and tpHZ are the same as tdis-
- F. tpZL and tpZH are the same as ten.
- G. tpHL and tpLH are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

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